

CERTIFICATE OF ACCREDITATION

HIROSE KOREA CO.,LTD

Accreditation No. : KT1149

Corporation Registration No. : 130111-0010693

Address of (Branch site) 143 Gongdan 1-daero, Siheung-si, Gyeonggi-do,
Laboratory : Republic of Korea

Date of Initial Accreditation : November 16, 2023

Validity of Accreditation : November 16, 2023 ~ November 15, 2027

Scope of Accreditation : Attached Annex

Date of issue : November 16, 2023

This testing laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to Joint ISO-ILAC-IAF Communiqué).



CHIN CHONGWOOK

Head

Korea Laboratory Accreditation Scheme

Korea Laboratory Accreditation Scheme

No. KT1149

03. Electrical Testing

03.004 Electrical materials and components

Test method	Materials/ Products	Standard designation	Test range	Site	Field testing
IEC 60512-2-1:2002	Connectors for electronic equipment	Connectors for electronic equipment - Tests and measurements - Part 2-1: Electrical continuity and contact resistance tests - Test 2a: Contact resistance - Millivolt level method	0 Ω ~ 3 kΩ	BS	N
IEC 60512-3-1:2002	Connectors for electronic equipment	Connectors for electronic equipment - Tests and measurements - Part 3-1: Insulation tests - Test 3a: Insulation resistance	0.1 MΩ ~ 50 GΩ	BS	N
IEC 60512-4-1:2003	Connectors for electronic equipment	Connectors for electronic equipment - Tests and measurements - Part 4-1: Voltage stress tests - Test 4a: Voltage proof	AC : 0 kV ~ 5.00 kV DC : 0 kV ~ 6.00 kV	BS	N
KS C 6040:2014	Connectors for electronic equipment	Method for test of connectors for electronic equipment 6.1 Voltage proof 6.2 Insulation resistance 6.4 Contact resistance at low voltage and low current	6.1 Voltage proof AC : 0 kV ~ 5.00 kV DC : 0 kV ~ 6.00 kV 6.2 Insulation resistance 0.1 MΩ ~ 50 GΩ 6.4 Contact resistance 0 Ω ~ 3 kΩ	BS	N

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No. KT1149

03. Electrical Testing

03.014 Environmental and Reliability

Test method	Materials/ Products	Standard designation	Test range	Site	Field testing
IEC 60068-2-14:2009	Connectors for electronic equipment	Environmental testing - Part 2-14: Tests - Test N: Change of temperature [Exception] 8. Test Nb : Change of temperature with specified rate of change 9. Test Nc : Rapid change of temperature (two-fluid-bath method)	High Temp. : +70 °C ~ +125 °C Low Temp. : -5 °C ~ -55 °C	BS	N
IEC 60068-2-1:2007	Connectors for electronic equipment	Environmental testing - Part 2-1: Tests -Test A: Cold	-55 °C ~ +5 °C	BS	N
IEC 60068-2-2:2007	Connectors for electronic equipment	Environmental testing - Part 2-2: Tests - Test B: Dry heat	+30 °C ~ +125 °C	BS	N
IEC 60068-2-78:2012	Connectors for electronic equipment	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	30 °C, 93 % R.H. 30 °C, 85 % R.H. 40 °C, 93 % R.H. 40 °C, 85 % R.H.	BS	N
IEC 60512-11-10:2002	Connectors for electronic equipment	Connectors for electronic equipment - Tests and measurements - Part 11-10: Climatic tests - Test 11j: Cold	-55 °C ~ +5 °C	BS	N
IEC 60512-11-3:2002	Connectors for electronic equipment	Connectors for electronic equipment - Tests and measurements - Part 11-3: Climatic tests - Test 11c: Damp heat, steady state	30 °C, 93 % R.H. 30 °C, 85 % R.H. 40 °C, 93 % R.H. 40 °C, 85 % R.H.	BS	N
IEC 60512-11-4:2002	Connectors for electronic equipment	Connectors for electronic equipment - Tests and measurements - Part 11-4: Climatic tests - Test 11d: Rapid change of temperature	High Temp. : +70 °C ~ +125 °C Low Temp. : -5 °C ~ -55 °C	BS	N
IEC 60512-11-9:2002	Connectors for electronic equipment	Connectors for electronic equipment - Tests and measurements - Part 11-9: Climatic tests - Test 11i: Dry heat	+30 °C ~ +125 °C	BS	N

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Test method	Materials/ Products	Standard designation	Test range	Site	Field testing
KS C 6040:2014	Connectors for electronic equipment	Method for test of connectors for electronic equipment 8.2 Temperature cycle 8.3 Damp heat, steady state 8.8 Dry heat 8.9 Cold	8.2 Temperature cycle High Temp. : +70 °C ~ +125 °C Low Temp. : -5 °C ~ -55 °C 8.3 Damp heat, steady state 40 °C, 93 % R.H. 8.8 Dry heat Temp. : +30 °C ~ +125 °C 8.9 Cold Temp. : -55 °C ~ +5 °C	BS	N
KS C IEC 60068-2- 14:2009	Connectors for electronic equipment	Environmental testing - Part 2-14: Tests - Test N: Change of temperature [Exception] 8. Test Nb : Change of temperature with specified rate of change 9. Test Nc : Rapid change of temperature (two-fluid-bath method)	High Temp. : +70 °C ~ +125 °C Low Temp. : -5 °C ~ -55 °C	BS	N
KS C IEC 60068-2- 1:2007	Connectors for electronic equipment	Environmental testing - Part 2-1: Tests -Test A: Cold	-55 °C ~ +5 °C	BS	N
KS C IEC 60068-2- 2:2007	Connectors for electronic equipment	Environmental testing - Part 2-2: Tests - Test B: Dry heat	+30 °C ~ +125 °C	BS	N
KS C IEC 60068-2- 78:2012	Connectors for electronic equipment	Environmental testing - Part 2-78: Tests - Test Cab: Damp heat, steady state	30 °C, 93 % R.H. 30 °C, 85 % R.H. 40 °C, 93 % R.H. 40 °C, 85 % R.H.	BS	N

End.